# **Capability analysis**

#### Menu: QCExpert Capability

This module computes the capability index,  $c_p$  and the performance index,  $p_p$ , based on data and user-specified limits. Additional values, like ARL are given as well. The module allows for one-sided specifications as well as for asymmetric (non-normal) distribution.

### Data and parameters

Measured values of the quality characteristics of interest are entered as data. The module expects that the data are in one column. Target value has to be specified in the Dialog panel. In addition, at least one of the specification limits has to be entered (LSL, *Lower Specification Limit* or USL, *Upper Specification Limit*). In the *Columns* field, data column is selected. One can specify, whether all data, marked data, or unmarked data will be used for computations in the *Data* field. In the *Plots* field, graphical output requests are to be specified. List of available plots appears in the paragraph 0 below.

When only one specification limit is defined for the process under control (no matter whether lower or upper), it is entered in the dialog panel, while the field for the other limit is left blank. A desired *Confidence level* can be specified as well. It is used subsequently for calculation of confidence interval, capability and performance indexes. *Cp limit* is the value, below which we consider the process as being not capable. In the Protocol output, all index values and their confidence interval limits smaller than Cp are marked in red. Usually, 1 is selected for Cp.

If the *Classical indexes* field is marked, classical capability and performance indexes:  $c_p$ ,  $c_{pk}$ ,  $c_{pm}$ ,  $p_p$ ,  $p_{pk}$ ,  $p_{pm}$  are computed, together with additional characteristics. Definitions of these indexes are shown below. When only one specification limit is specified, classical indexes are not computed. Then, one has to mark the *General indexes* selection – and the  $c_{pk}^*$  index (based on probabilistic grounds) is computed. This generalized index can be used for one-sided specification limit or asymmetric data, violating the usual normality assumption. (Distributional normality test can be found in the *Elementary statistics* module. If the Asymmetric data distribution selection is checked, the software allows for a possibility that the data come form asymmetric (skewed) distribution. The  $c_{pk}$ calculation is then adjusted via preliminary application of the exponential transformation of the data. Quantile function  $F^{-1}$  value (needed during  $c_{pk}^*$  calculations) is computed after the transformation. Warning: if the Asymmetric data distribution selection is not checked, the software goes straight ahead and uses "forcefully" normal model, even though the true data generating distribution is not normal. Hence, if one is not sure about distributional symmetry, it is a good strategy to leave the selection checked. Further detail about properties and motivation of the exponential data transformation can be found in the manual for the Transformation module. If the data are not normal, classical indexes commonly give unrealistically optimistic impressions. They often overestimate true values (although they can be underestimate as well). Hence, if the data are not approximately normal, the classical indexes should not be used.

Canability				
Capability				
Task name	Prod Line 33	19 A		
			Graph	
Target value, T	5		🔽 Histogra	m
Lower limit, LSL	3		🔽 Distribut	ion function
	7		🔽 Probabil	ity density
Upper limit, USL	7		🔽 Asymetr	ic distribution
Data			·	
<ul> <li>All</li> </ul>	0	Marked	0	Unmarked
Columns				
X Y		🔽 Cla	assical indices	🔽 General indices
Y		🔽 Asj	ymetric data	
		Signi	ficance level	0.05
		-	cceptable Cp	1
7 Help	1		🗙 Back	✓ <u>□</u> K

Fig. 1 Dialog panel for Capability

$$c_{p} = \frac{USL - LSL}{6\sigma_{c}}, c_{pk} = \frac{\min(USL - \bar{x}, \bar{x} - LSL)}{3\sigma_{c}}, c_{pm} = \frac{(USL - LSL)}{6\sqrt{\sigma_{c}^{2} + (x - T)^{2}}}$$

$$p_{p} = \frac{USL - LSL}{6\sigma_{p}}, \ p_{pk} = \frac{\min(USL - x, x - LSL)}{3\sigma_{p}}, \ p_{pm} = \frac{(USL - LSL)}{6\sqrt{\sigma_{p}^{2} + (x - T)^{2}}}$$

$$\sigma_{c} = \sqrt{\frac{1}{n - 1}\sum_{1}^{n} [x_{i} - x]^{2}}, \ \sigma_{p} = \frac{1}{d_{2}} \frac{\sum_{2}^{n} |x_{i} - x_{i-1}|}{n - 1}, \ kde \ d_{2} = 1.128$$

$$p_{zm} = F_{N} \left(\frac{x - LSL}{\sigma_{c}}\right) + 1 - F_{N} \left(\frac{USL - x}{\sigma_{c}}\right)$$

$$ARL = 1/p_{zm}$$

$$c_{pk}^{*} = -\frac{1}{3}F^{-1}\{1/ARL\},$$

where  $F^{-1}$  is the inverse function to the distribution function (or the quantile function) for the normal distribution.

**Remark:** Because the estimate is generally not equal to the true value, it is more appropriate not to concentrate only on the point estimate, but to consider associated confidence interval as well. A particular, rater more conservative strategy is typically suggested: behave as if the true the lower confidence interval limit was equal to the true index value. Remember that, for instance if the index comes out as  $c_p=1.001$  with associated confidence interval stretching from 0.8 to 1.2, that the process

is very likely not capable  $(c_p < 1)!$  If the index comes out as  $c_p = 1.2$ , with the confidence interval ranging from 1.0 to 1.4, it is very unlikely that the process is not capable.

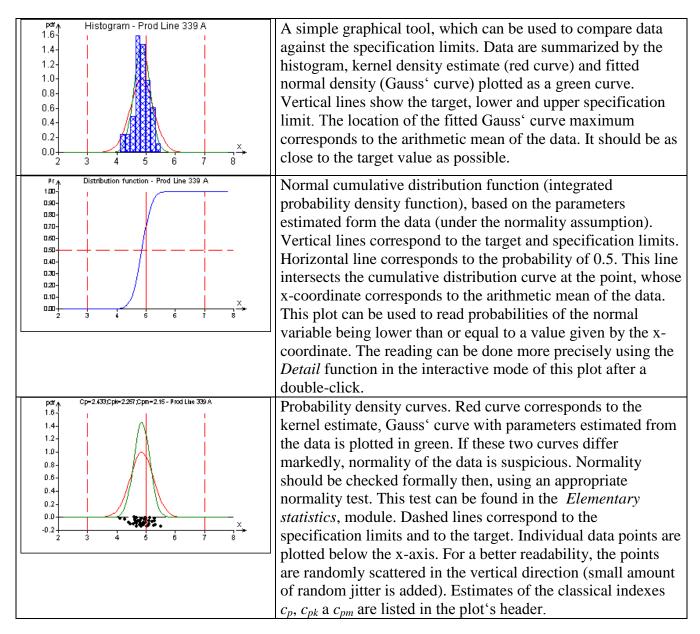
# Protocol

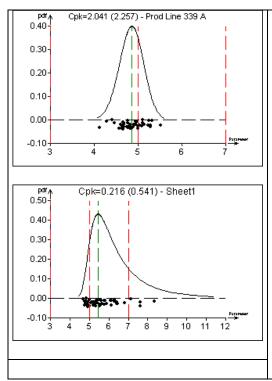
11010001	
Capability and performance	Normal distribution based calculations are performed only when both
under the normality	specification limits are given. When only one limit is given, report
assumption	contains items from the "Cpk for asymmetrically distributed data".
Project name	Name of the data spreadsheet
- Jerri Maria	
Target value	User-specified target parameter value.
Specification limits	eser speented unger parameter value.
4	Lower specification limit (if specified by the user).
	Upper specification limit (if specified by the user).
CP IIIIII	Lowest capability resp. performance index value that is acceptable.
	Values, smaller than the CP limit will be marked in red.
Capability indexes	
· · · · · · · · · · · · · · · · · · ·	Arithmetic average computed from the data.
Standard deviation	Standard deviation, estimated from the data, $\sigma_C$
+/- 3sigma	Lower and upper limit of the $\pm 3\sigma_C$ interval around the arithmetic mean
Z-score	
Index	
	Classical capability index value, $c_p$ computed from $\sigma_C$
Cpk	
-	
	Classical capability index value, $c_{pm}$ computed from $\sigma_C$
	Lower limit of the confidence interval for a particular index.
Upper limit	Upper limit of the confidence interval for a particular index.
Performance limits	
	Arithmetic mean computed from the data
	Standard deviation computed from the data, $\sigma_C$
	Lower and upper limit of $\pm 3\sigma_C$ interval around the arithmetic mean
Z-score	Z-scores correspond to the lower and upper data part
Index	
Pp	Classical performance index value, $p_p$ computed from $\sigma_P$
Ppk	
Ppm Ppm	
	Lower limit of the confidence interval for a particular index.
	▲ ▲
	Upper limit of the confidence interval for a particular index.
Drohobility of aveca the	Drobability that the upper on lower analitication limit a milling
Probability of exceeding	
specification limits	
	next measurement will fall above upper or below lower specification
	limit.
Expected relative frequency	It can be understood as the expected number of the measurements
of exceeding in %	<b>e</b> 11 1
	100 measurements taken under the same circumstances.
Expected relative frequency	It can be understood as the expected number of the measurements

of exceeding in PPM	falling above the upper or below the lower specification limit in the next
	1,000,000 measurements taken under the same circumstances.
	Probability that any of the specification limits will be exceeded. This
the SL	number can be understood as the probability that the next measurement
Delative fraguency of heing	will fall beyond any of the specification limits.
Relative frequency of being out of the SL in %	It can be understood as the expected number of the measurements falling beyond any of the specification limits in the next 100
out of the SL III 70	measurements taken under the same circumstances.
Relative frequency of being	It can be understood as the expected number of the measurements
out of the SL in PPM	falling beyond any of the specification limits in the next 1000000
out of the SE in TTW	measurements taken under the same circumstances.
ARL	Average Run Length is the expected number of measurements between
	two consecutive specification limit exceeding.
Cpk for asymmetrically	
distributed data	
Sample size	Number of the data points used for computations.
Corrected average	Expected value estimate, corrected for the data distribution skewness.
	When the data are symmetrically distributed, this characteristic is equal
	to the arithmetic average, see the Transformation module.
	User-defined target.
CP limit	Lowest acceptable $c_p$ value. Values lower than this limit will be marked
	in red.
Specification limits	
Probability of exceeding	Probability that the upper, or lower specification limit, $p_{zm}$ will be
	exceeded. This number can be understood as the probability that the
	exceeded. This number can be understood as the probability that the next measurement will fall above upper or below lower specification
Expected relative frequency	exceeded. This number can be understood as the probability that the next measurement will fall above upper or below lower specification limit.
Expected relative frequency	exceeded. This number can be understood as the probability that the next measurement will fall above upper or below lower specification limit. It can be understood as the expected number of the measurements
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### Graphs

The capability module provides four plot types: three show density and one distribution function. The first three plots, that is: Histogram, Distribution function and a Density are plotted only when the *Classical indexes* selection is checked. The last plot: Density of the transformed data is plotted only when the *General index* selection is checked.





Probability density curve for the transformed data. The meaning of the plot is very similar to the previous one. The density is estimated via the exponential transformation. More details about the transformation can be found in the Transformation module. If the *Asymmetric data distribution* is not checked before the calculations, transformation is not used and normal density curve is plotted. Asymmetry of the data distribution can be checked graphically by inspection of the probability density curve on this plot. The  $c_{pk}^*$  index estimate is listed in the plot's header. When both specification limits are given, the classical  $c_{pk}$  index is listed in parenthesis as well. If the two values differ markedly,  $c_{pk}^*$  should be used. Illustrative examples on the left panel here show curve shapes for symmetric and asymmetric data distributions.